

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Seiya YAMADA, et al.

FILING DATE

August 4, 2003

GROUP

1764

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
|---------------------|----|--------------------|------|------|-------|--------------|-------------------------------|
| | AA | | | | | | |
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FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | TRANSLATION | |
|----|----|--------------------|------------|-------------------------------|-------------|----|
| | | | | | YES | NO |
| JW | AO | 2001-42091 | 02/16/2001 | JAPAN (with English Abstract) | | X |
| JW | AP | 60-106000 | 06/11/1985 | JAPAN | | X |
| | AQ | 2001-108792 | 04/20/2001 | JAPAN (with English Abstract) | | X |
| | AR | | | | | |
| | AS | | | | | |
| | AT | | | | | |
| | AU | | | | | |
| | AV | | | | | |

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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| | AW | |
| | AX | |
| | AY | |
| | AZ | |

☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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|---|----|---|---------|--------------------------------------|----------------------------|-------------------------------|--|
| Form PTO 1449 (Modified) | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY DOCKET NO. 241206US3X | | SERIAL NO. New Application | |
| LIST OF REFERENCES CITED BY APPLICANT | | | | APPLICANT Seiya YAMADA, et al. | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | | DOCUMENT NUMBER | DATE | COUNTRY | TRANSLATION YES NO | | |
| jcr | AO | 5-31759 | 5/13/93 | Japan | | | X |
| | AP | | | | | | |
| | AQ | | | | | | |
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| | AU | | | | | | |
| | AV | | | | | | |
| OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) | | | | | | | |
| jcr | AW | "2002 FALL MEETING OF THE ATOMIC ENERGY SOCIETY OF JAPAN", August 5, 2002 | | | | | |
| | AX | | | | | | |
| | AY | | | | | | |
| | AZ | | | | | | <input type="checkbox"/> Additional References sheet(s) attached |
| Examiner | | | | | Date Considered | | |
| <small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small> | | | | | | | |